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		Results
#1	((first deposition<in>metadata) <and> (second deposition<in>metadata))	1
#2	((first deposition<in>metadata) <and> (second deposition<in>metadata))	1
#3	deposition layer	81
#4	((deposition layer)<AND>(spacdr<in>metadata))	0
#5	deposition layer	81
#6	((deposition layer)<AND>(spacer<in>metadata))	1
#7	deposition layer	81
#8	((deposition layer)<AND>(flash memory<in>metadata))	0
#9	deposition layer	81
#10	((deposition layer)<AND>(split gate<in>metadata))	0
#11	deposition layer	81
#12	((first layer<and>second layer)<and> (semiconductor<in>metadata)) <and> (pyr >= 1950 <and> pyr <= 2004)	233
#13	((((first layer<and>second layer)<and> (semiconductor<in>metadata)) <and> (pyr >= 1950 <and> pyr <= 2004))<AND>(thickness<in>metadata))	21

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